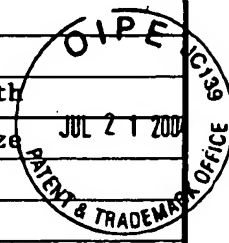


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Substitute for form 1449B/PTO  <b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>  (Use as many sheets as necessary)		<b>Complete if Known</b>	
		Application Number	10/720,763
		Filing Date	Even Date Herewith
		First Named Inventor	Nikolay I. Agladze
		Art Unit	2877
		Examiner Name	Samuel A. Turner
Sheet 1 of 1	Attorney Docket Number	CRF D-3094/US	



NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No. <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T <sup>2</sup>
SAT	1	"Digital array scanned interferometer: sensors and results," Wm Hayden Smith and Philip D. Hammer; Applied Optics, Vol. 35, No. 16, June 1996	
↑	2	"Photographic Method of Recording in Fourier Spectrometry," I.P. Petrov and B.N. Grechushnikov; Optics and Spectroscopy, 19, p. 82-83 (1965)	
	3	"Computational Aberration Correction for an Arbitrary Linear Imaging System," L. J. Allen, M. P. Oxley, and D. Paganin; Physical Review Letters, Vol. 87, No. 12, 17 September 2001	
	4	"Effects of aberrations on spatially modulated Fourier transform spectrometers," R. Glenn Sellar, J. Bruce Rafert; Optical Engineering, September 1994, Vol. 33, No. 9/3087	
	5	"Fourier transform spectrometer with a self-scanning photodiode array," Takayuki Okamoto, Satoshi Kawata, and Shigeo Minami; Applied Optics, 15 January 1984, Vol. 23, No. 2	
	6	"Spatially Encoded Fourier Transform Spectroscopy in the Ultraviolet to Near-Infrared," Jonathan V. Sweedler and M. Bonner Denton; Applied Spectroscopy, Vol. 43, No. 8, 1989	
↓	7	"Monolithic Fourier-transform imaging spectrometer," J. Bruce Rafert, R. Glenn Sellar, and Joel H. Blatt; Applied Optics, Vol. 34, No. 31, 1 November 1995	
SAT	8	"Phase Retrieval through Focus Variation for Ultra-Resolution in Field-Emission Transmission Electron Microscopy," Wim Coene and Guido Janssen, Marc Op de Beeck and Dirk Van Dyck; Physical Review Letters, Vol. 69, No. 26, 28 December 1992	

Examiner Signature	S.A. Turner	Date Considered	11-12-04
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\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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## INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(use as many sheets as necessary)

**Complete if Known**

Application Number	10/720,763
Filing Date	Even Date Herewith
First Named Inventor	Nikolay I. Agladze
Group Art Unit	2877
Examiner Name	Samuel A. Turner
Attorney Docket Number	CRF D-3094/US

Sheet 1 of 1

## U.S. PATENT DOCUMENTS

[illegible]

**FOREIGN PATENT DOCUMENTS**

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**Examiner  
Signature**

S.A. TUNGA

Date	
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